



APT8014L2LL

800V 52A 0.140Ω

## POWER MOS 7™

Power MOS 7™ is a new generation of low loss, high voltage, N-Channel enhancement mode power MOSFETs. Both conduction and switching losses are addressed with Power MOS 7™ by significantly lowering  $R_{DS(ON)}$  and  $Q_g$ . Power MOS 7™ combines lower conduction and switching losses along with exceptionally fast switching speeds inherent with APT's patented metal gate structure.



- Lower Input Capacitance
- Increased Power Dissipation
- Lower Miller Capacitance
- Easier To Drive
- Lower Gate Charge,  $Q_g$
- Popular TO-264 MAX Package

## MAXIMUM RATINGS

All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	APT8014L2LL	UNIT
$V_{DSS}$	Drain-Source Voltage	800	Volts
$I_D$	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	52	Amps
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	208	
$V_{GS}$	Gate-Source Voltage Continuous	$\pm 30$	
$V_{GSM}$	Gate-Source Voltage Transient	$\pm 40$	Volts
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	890	Watts
	Linear Derating Factor	7.12	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$T_L$	Lead Temperature: 0.063" from Case for 10 Sec.	300	
$I_{AR}$	Avalanche Current <sup>①</sup> (Repetitive and Non-Repetitive)	52	Amps
$E_{AR}$	Repetitive Avalanche Energy <sup>①</sup>	50	
$E_{AS}$	Single Pulse Avalanche Energy <sup>④</sup>	3200	mJ

## STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-Source Breakdown Voltage ( $V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$ )	800			Volts
$I_{D(on)}$	On State Drain Current <sup>②</sup> ( $V_{DS} > I_{D(on)} \times R_{DS(on)}$ Max, $V_{GS} = 10\text{V}$ )	52			Amps
$R_{DS(on)}$	Drain-Source On-State Resistance <sup>②</sup> ( $V_{GS} = 10\text{V}$ , $0.5 I_{D[Cont.]}$ )			0.140	Ohms
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{DS} = V_{DSS}$ , $V_{GS} = 0\text{V}$ )			100	$\mu\text{A}$
	Zero Gate Voltage Drain Current ( $V_{DS} = 0.8 V_{DSS}$ , $V_{GS} = 0\text{V}$ , $T_C = 125^\circ\text{C}$ )			500	
$I_{GSS}$	Gate-Source Leakage Current ( $V_{GS} = \pm 30\text{V}$ , $V_{DS} = 0\text{V}$ )			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage ( $V_{DS} = V_{GS}$ , $I_D = 5\text{mA}$ )	3		5	Volts



CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

APT Website - <http://www.advancedpower.com>

USA

405 S.W. Columbia Street

Bend, Oregon 97702-1035

Phone: (541) 382-8028

FAX: (541) 388-0364

## DYNAMIC CHARACTERISTICS

APT8014L2LL

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		7710		pF
$C_{oss}$	Output Capacitance			1480		
$C_{rss}$	Reverse Transfer Capacitance			244		
$Q_g$	Total Gate Charge ③	$V_{GS} = 10V$ $V_{DD} = 0.5 V_{DSS}$ $I_D = I_{D[\text{Cont.}]} @ 25^\circ C$		284		nC
$Q_{gs}$	Gate-Source Charge			37		
$Q_{gd}$	Gate-Drain ("Miller") Charge			161		
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$ $V_{DD} = 0.5 V_{DSS}$ $I_D = I_{D[\text{Cont.}]} @ 25^\circ C$ $R_G = 0.6\Omega$		20		ns
$t_r$	Rise Time			19		
$t_{d(off)}$	Turn-off Delay Time			69		
$t_f$	Fall Time			15		

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$I_S$	Continuous Source Current (Body Diode)			52	
$I_{SM}$	Pulsed Source Current ① (Body Diode)			208	Amps
$V_{SD}$	Diode Forward Voltage ② ( $V_{GS} = 0V$ , $I_S = -I_{D[Cont.]}$ )			1.3	Volts
$t_{rr}$	Reverse Recovery Time ( $I_S = -I_{D[Cont.]}$ , $dl_S/dt = 100A/\mu s$ )		930		ns
$Q_{rr}$	Reverse Recovery Charge ( $I_S = -I_{D[Cont.]}$ , $dl_S/dt = 100A/\mu s$ )		29.0		$\mu C$
$dv/dt$	Peak Diode Recovery $dv/dt$ ⑤			10	V/ns

## THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.14	
$R_{\theta JA}$	Junction to Ambient			40	°C/W

① Repetitive Rating: Pulse width limited by maximum junction temperature

② Pulse Test: Pulse width < 380 μs, Duty Cycle < 2%

<sup>③</sup> See MIL-STD-750 Method 3471.

④ Starting  $T_i = +25^\circ\text{C}$ ,  $L = 2.37\text{mH}$ ,  $R_G = 25\Omega$ , Peak  $I_1 = 52\text{A}$

⑤ dv/dt numbers reflect the limitations of the test circuit rather than the

device itself.  $I_{\text{C}} \leq -I_{\text{Dmax},-1}$ ,  $\frac{di}{dt} \leq 700\text{A}/\mu\text{s}$ ,  $V_{\text{DS}} \leq V_{\text{DSS}}$ ,  $T \leq 150^\circ\text{C}$

**APT Reserves the right to change, without notice, the specifications and information contained herein.**

## TO-264 MAX<sup>TM</sup>(L2) Package Outline

